

# N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω) Max.	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
	0.0048 at V <sub>GS</sub> = 10 V	60				
80	0.0050 at V <sub>GS</sub> = 7.5 V	60	25 nC			
	0.0064 at V <sub>GS</sub> = 4.5 V	60				

#### **FEATURES**

- TrenchFET® power MOSFET
- 100 % R<sub>g</sub> and UIS tested



#### **APPLICATIONS**

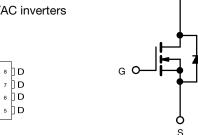
- · Primary side switching
- Synchronous rectification
- DC/AC inverters

Top View

s [

G [

S [] 3





DFN5	5X6
Top View	<b>Bottom View</b>

PIN1

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	80	V	
Gate-Source Voltage		$V_{GS}$	± 20		
	T <sub>C</sub> = 25 °C		60 <sup>a</sup>		
Continuous Drain Current /T 150 °C\	T <sub>C</sub> = 70 °C		60 <sup>a</sup>		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	23.8 b, c		
	T <sub>A</sub> = 70 °C		19 <sup>b, c</sup>		
Pulsed Drain Current (t = 300 μs)		I <sub>DM</sub>	100	A	
Ocalia a a Ocala Buia Biada Ocala	T <sub>C</sub> = 25 °C		60 <sup>a</sup>		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	5.6 b, c		
Single Pulse Avalanche Current  L = 0.1 m		I <sub>AS</sub>	35		
Single Pulse Avalanche Energy	L = U. I IIII	E <sub>AS</sub>	61	mJ	
	T <sub>C</sub> = 25 °C		104		
Maximum Dawar Dissination	T <sub>C</sub> = 70 °C		66.6	10/	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	6.25 <sup>b, c</sup>	W	
	T <sub>A</sub> = 70 °C		4 b, c		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	۰,	
Soldering Recommendations (Peak Temperatur		260	°C		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient b, f	t ≤ 10 s	R <sub>thJA</sub>	15	20	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	0.9	1.2	C/VV		

#### **Notes**

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
  d. The DFN 5Xx6 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 54 °C/W.



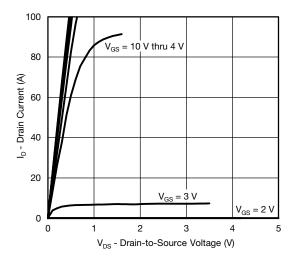
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	•					
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L 050 A	-	47	-	1400
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA	-	-5.7	-	mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.2	-	2.8	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
7 0 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	I <sub>DSS</sub>	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V	-	-	1	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C	-	-	10	μA
On-State Drain Current a	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30	-	-	Α
	\(\sigma \)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A	-	0.0048	-	<u> </u>
Drain-Source On-State Resistance a	R <sub>DS(on)</sub>	$V_{GS} = 7.5 \text{ V}, I_D = 20 \text{ A}$	-	0.0050	-	Ω
	`	$V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$	-	0.0064	-	
Forward Transconductance a	9 <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_{D} = 20 \text{ A}$	-	68	-	S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>		-	2800	-	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	1100	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	93	-	
Total Gate Charge	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$	-	57		
		$V_{DS} = 40 \text{ V}, V_{GS} = 7.5 \text{ V}, I_D = 20 \text{ A}$	-	42	63	nC
			-	25	38	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$	-	8.5	-	
Gate-Drain Charge	$Q_{gd}$		-	10	-	
Output Charge	Q <sub>oss</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V	ı	70	105	1
Gate Resistance	$R_{g}$	f = 1 MHz	0.3	0.95	1.9	Ω
Turn-On Delay Time	t <sub>d(on)</sub>		-	9	18	
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 2 \Omega$	ı	12	24	1
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		34	68	1
Fall Time	t <sub>f</sub>		-	7	14	1
Turn-On Delay Time	t <sub>d(on)</sub>		ı	16	32	ns -
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 2 \Omega$	ı	15	30	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 7.5 \text{ V}, R_g = 1 \Omega$	-	32	64	
Fall Time	t <sub>f</sub>		-	8	16	
<b>Drain-Source Body Diode Characteristic</b>	s					
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C	-	-	60	^
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>		-	-	100	A
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 5 A	-	0.73	1.1	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	53	105	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 00 A 41/44 400 A / - T 05 20	-	65	130	nC
Reverse Recovery Fall Time	ta	$t_a$ $t_F = 20 \text{ A, di/dt} = 100 \text{ A/µs, } t_J = 25 \text{ C}$		25	-	ns
Reverse Recovery Rise Time	t <sub>b</sub>			28	-	

#### Notes

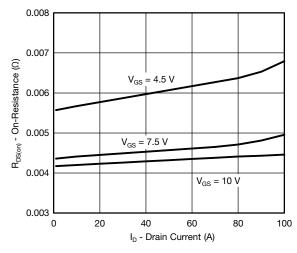
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

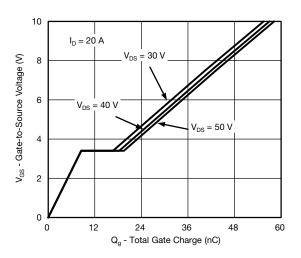




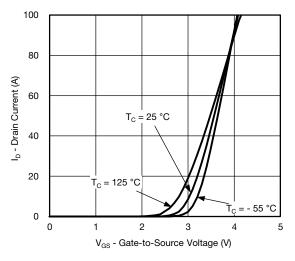




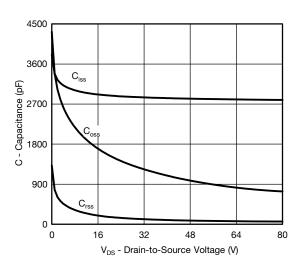
On-Resistance vs. Drain Current



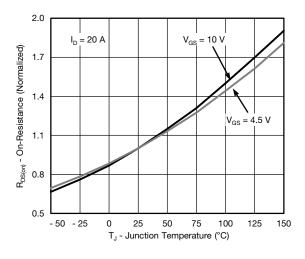
**Gate Charge** 



**Transfer Characteristics** 

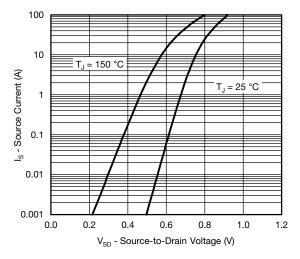


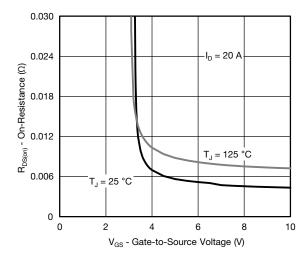
Capacitance



On-Resistance vs. Junction Temperature

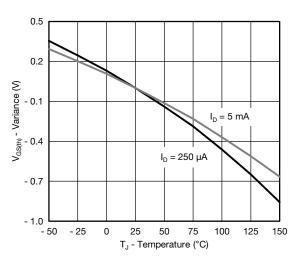


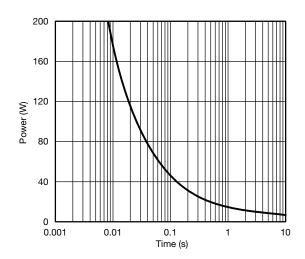




Source-Drain Diode Forward Voltage

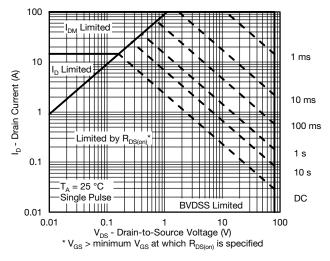






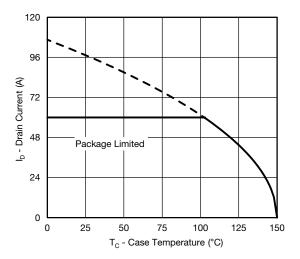
Threshold Voltage

Single Pulse Power, Junction-to-Ambient

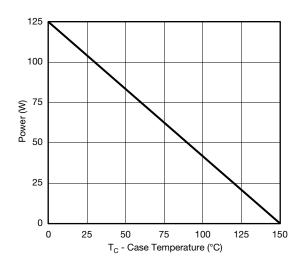


Safe Operating Area, Junction-to-Ambient

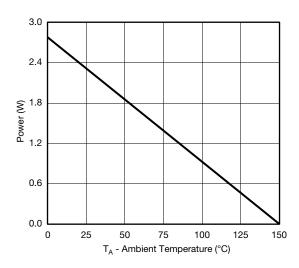




#### **Current Derating\***



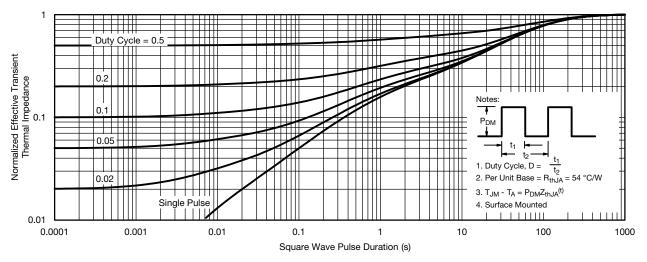




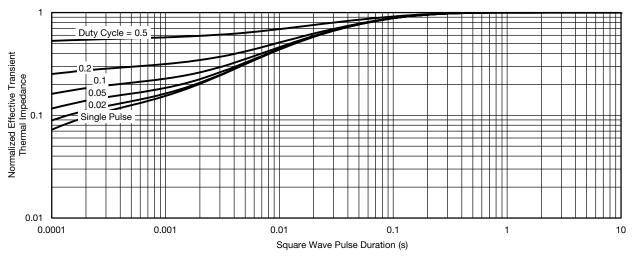
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J \text{ (max.)}} = 150 \,^{\circ}\text{C}$ , using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





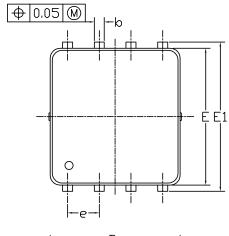
Normalized Thermal Transient Impedance, Junction-to-Ambient

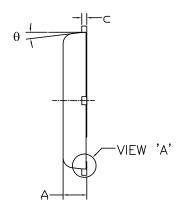


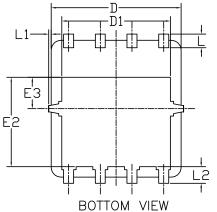
Normalized Thermal Transient Impedance, Junction-to-Case

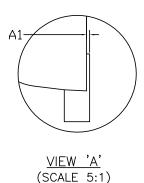


DFN5x6\_8L\_EP1\_P PACKAGE OUTLIN

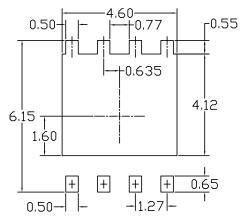








RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
SIMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
A	0.85	0. 95	1.00	0.033	0.037	0.039
A1	0.00		0.05	0.000		0.002
b	0.30	0.40	0.50	0.012	0.016	0.020
С	0.15	0. 20	0. 25	0.006	0.008	0.010
D	5. 10	5. 20	5. 30	0. 201	0. 205	0. 209
D1	4. 25	4. 35	4. 45	0. 167	0.171	0. 175
E	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242
E2	3. 525	3. 625	3. 725	0.139	0.143	0. 147
E3	1. 175	1. 275	1.375	0.046	0.050	0.054
e	1. 27 BSC				0.050 BSC	
L	0.45	0. 55	0.65	0.018	0.022	0.026
L1	0		0. 15	0		0.006
L2	0.68 REF			0.027 REF		
θ	0°		10°	0°		10°

NOTE UNIT: mm

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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